Abstracts

Experimental Investigation of the Temperature Dependence of PHEMT Noise Parameters

S. Lardizabal, L. Dunleavy, W. Yau and S. Bar. "Experimental Investigation of the Temperature Dependence of PHEMT Noise Parameters." 1994 MTT-S International Microwave Symposium Digest 94.2 (1994 Vol. II [MWSYM]): 845-848.

A general temperature dependent noise equivalent circuit parameter modeling procedure for MESFETs and PHEMTs is described. The noise source variations are fit to linear functions of temperature over the 25 to 100°C range. The originality of the contribution lies in the combined treatment of the temperature dependence of both the small signal model and the internal noise sources.

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